

(19) World Intellectual Property
Organization
International Bureau



(43) International Publication Date
24 February 2005 (24.02.2005)

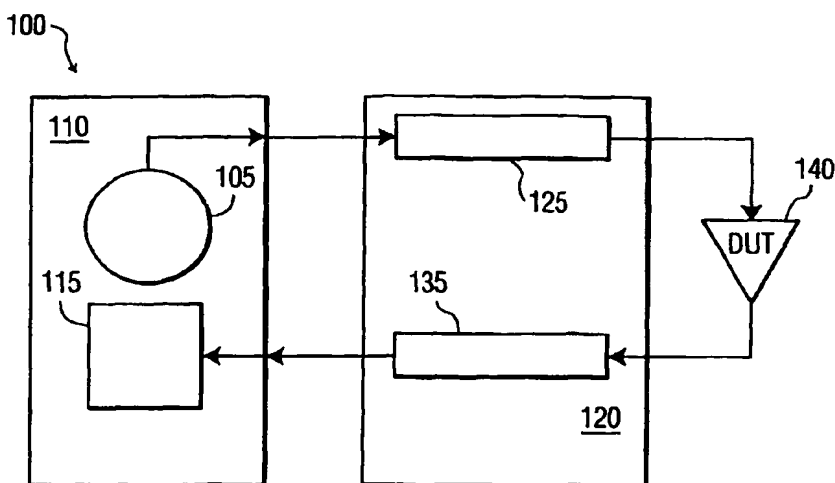
PCT

(10) International Publication Number
WO 2005/017542 A3

- (51) International Patent Classification⁷: **G01R 31/28**, 35/00
- (74) Common Representative: **KONINKLIJKE PHILIPS ELECTRONICS, N.V.**; c/o Shannon Lester, 1109 McKay Drive, M/S-SJ41, San Jose, CA 95131-1706 (US).
- (21) International Application Number: PCT/IB2004/051461
- (81) Designated States (unless otherwise indicated, for every kind of national protection available): AE, AG, AL, AM, AT, AU, AZ, BA, BB, BG, BR, BW, BY, BZ, CA, CH, CN, CO, CR, CU, CZ, DE, DK, DM, DZ, EC, EE, EG, ES, FI, GB, GD, GE, GH, GM, HR, HU, ID, IL, IN, IS, JP, KE, KG, KP, KR, KZ, LC, LK, LR, LS, LT, LU, LV, MA, MD, MG, MK, MN, MW, MX, MZ, NA, NI, NO, NZ, OM, PG, PH, PL, PT, RO, RU, SC, SD, SE, SG, SK, SL, SY, TJ, TM, TN, TR, TT, TZ, UA, UG, US, UZ, VC, VN, YU, ZA, ZM, ZW.
- (22) International Filing Date: 14 August 2004 (14.08.2004)
- (25) Filing Language: English
- (26) Publication Language: English
- (30) Priority Data: 60/495,152 14 August 2003 (14.08.2003) US
- (71) Applicant (for all designated States except US): **KONINKLIJKE PHILIPS ELECTRONICS, N.V.** [NL/NL]; Groenewoudseweg 1, NL-5621 BA Eindhoven (NL).
- (84) Designated States (unless otherwise indicated, for every kind of regional protection available): ARIPO (BW, GH, GM, KE, LS, MW, MZ, NA, SD, SL, SZ, TZ, UG, ZM, ZW), Eurasian (AM, AZ, BY, KG, KZ, MD, RU, TJ, TM), European (AT, BE, BG, CH, CY, CZ, DE, DK, EE, ES, FI, FR, GB, GR, HU, IE, IT, LU, MC, NL, PL, PT, RO, SE, SI, SK, TR), OAPI (BF, BJ, CF, CG, CI, CM, GA, GN, GQ, GW, ML, MR, NE, SN, TD, TG).
- (72) Inventors; and
- (75) Inventors/Applicants (for US only): **VISSER, Hendrik** [NL/US]; 1109 McKay Drive, M/S-SJ41, San Jose, CA 95131-1706 (US). **SPAIN, Sherry** [US/US]; P.O. Box 3001, Briarcliff Manor, NY 10510-8001 (US).

[Continued on next page]

(54) Title: CALIBRATION OF TESTER AND TESTBOARD BY GOLDEN SAMPLE



(57) Abstract: In performing testing on Automatic Test Equipment (ATE) it is a challenge to accurately generate and measure RF (radio frequency) power. In an example embodiment, in a test apparatus (100) used for measuring the input and output characteristics of an amplifier (140), there is a method for determining test program parameters. The method (200) comprises calculating input loss from the test apparatus power source to the input of the amplifier (220), defining an input loss correction factor. The output loss from the amplifier output (220) to the power meter of the test apparatus is calculated, defining an output loss correction factor. Using the input loss correction factor (230), a real input power level is determined and using the output loss correction factor (230), a real output level is determined.

**Declarations under Rule 4.17:**

- as to applicant's entitlement to apply for and be granted a patent (Rule 4.17(ii)) for the following designations AE, AG, AL, AM, AT, AU, AZ, BA, BB, BG, BR, BW, BY, BZ, CA, CH, CN, CO, CR, CU, CZ, DE, DK, DM, DZ, EC, EE, EG, ES, FI, GB, GD, GE, GH, GM, HR, HU, ID, IL, IN, IS, JP, KE, KG, KP, KR, KZ, LC, LK, LR, LS, LT, LU, LV, MA, MD, MG, MK, MN, MW, MX, MZ, NA, NI, NO, NZ, OM, PG, PH, PL, PT, RO, RU, SC, SD, SE, SG, SK, SL, SY, TJ, TM, TN, TR, TT, TZ, UA, UG, UZ, VC, VN, YU, ZA, ZM, ZW, ARIPO patent (BW, GH, GM, KE, LS, MW, MZ, NA, SD, SL, SZ, TZ, UG, ZM, ZW), Eurasian patent (AM, AZ, BY, KG, KZ, MD, RU, TJ, TM), European patent (AT, BE, BG, CH, CY, CZ, DE, DK, EE, ES, FI, FR, GB, GR, HU, IE, IT, LU, MC, NL, PL, PT, RO, SE, SI, SK, TR), OAPI patent (BF, BJ, CF, CG, CI, CM, GA, GN, GQ, GW, ML, MR, NE, SN, TD, TG)

- as to the applicant's entitlement to claim the priority of the earlier application (Rule 4.17(iii)) for all designations

Published:

- with international search report
— before the expiration of the time limit for amending the claims and to be republished in the event of receipt of amendments

(88) Date of publication of the international search report:

30 June 2005

For two-letter codes and other abbreviations, refer to the "Guidance Notes on Codes and Abbreviations" appearing at the beginning of each regular issue of the PCT Gazette.